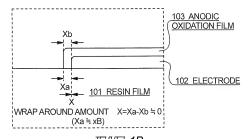
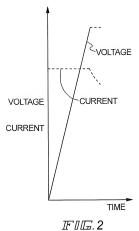
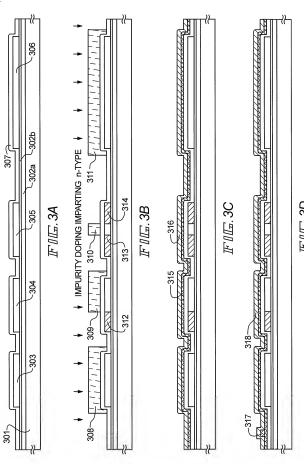


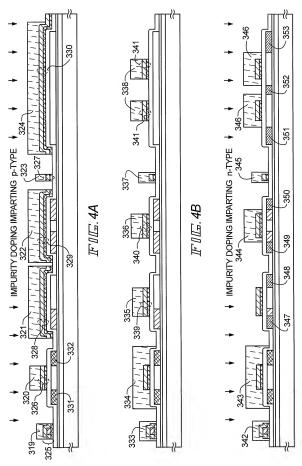
FI匠.1A SEM PHOTOGRAPH (CROSS SECTION)



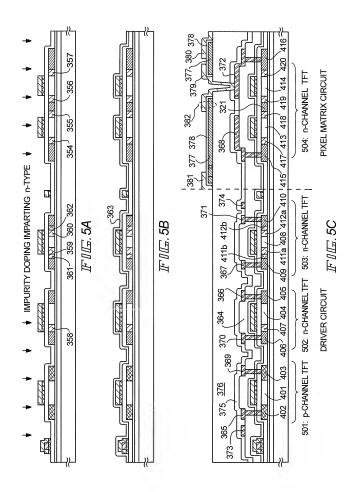


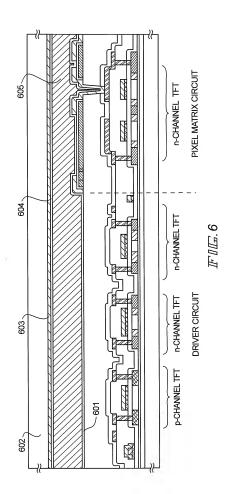


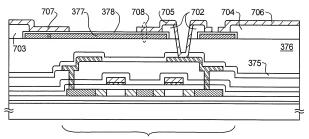
IF [15]: 3D



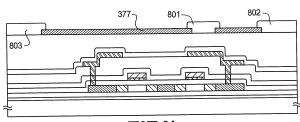
IF [[1]]. 4C

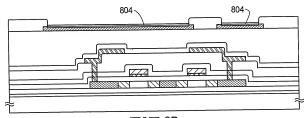




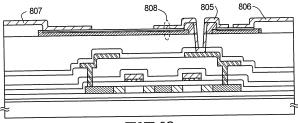


701: n-CHANNEL TFT

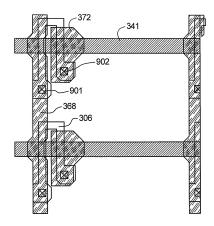




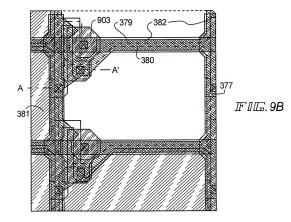
ℱⅅ⊑.8B

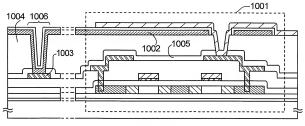


ℱⅅ<u></u>.8C

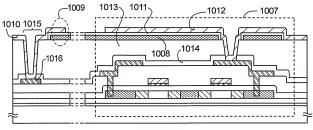


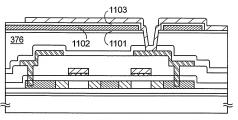
*₮ॗॗॗॗॗॗॗॗॗॗॗॗॗॗ.*9A



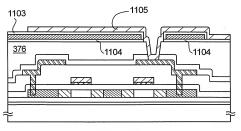


IF □ □ □ . 10A

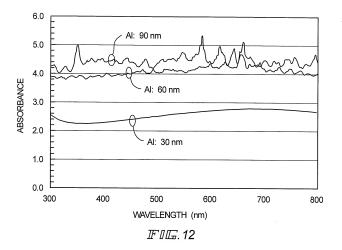


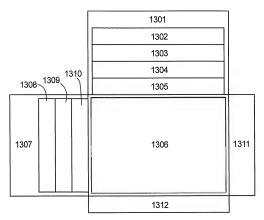


IF [[[□]. 11A

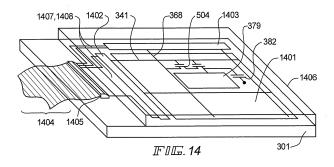


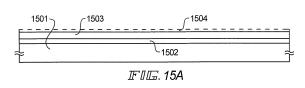
IF □ □ □ . 11B



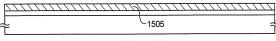


IF II III. 13

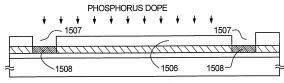




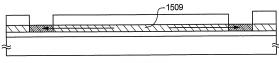


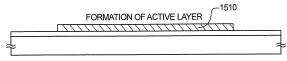


IF II II. 15B

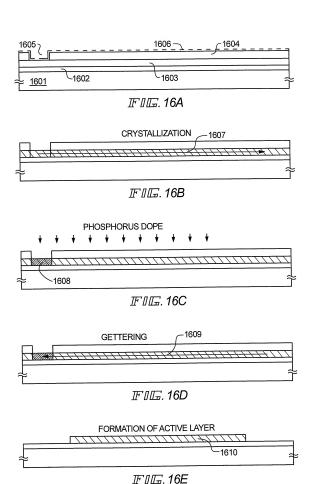


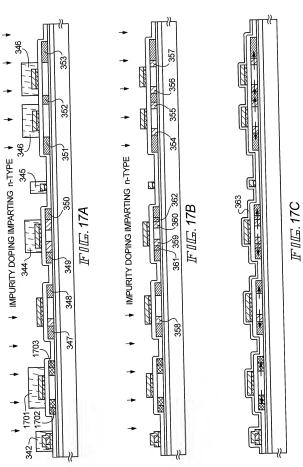
IF II III. 15C

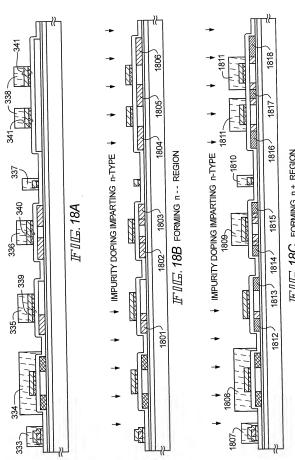




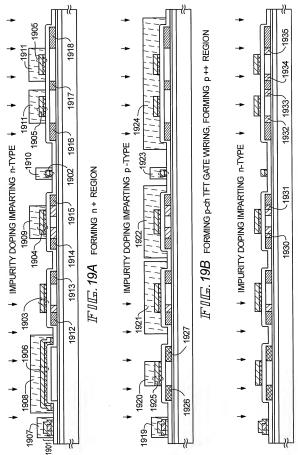
正尼.15E



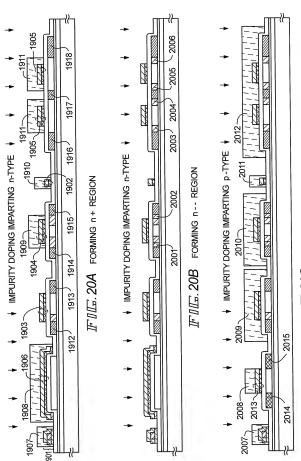




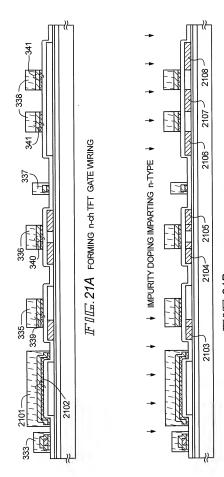
IF II II. 18C FORMING n+ REGION



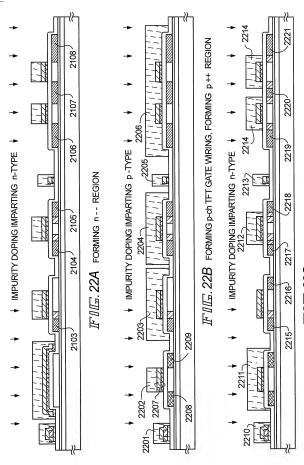
IF III. 19C FORMING n -- REGION



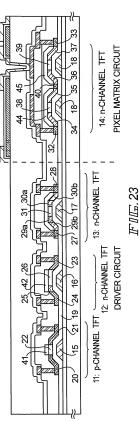
 $I\!\!FIII\!\!II$, 20C forming p-ch tft gate wiring, forming p++ region



IF [[I.]. 21B FORMING n -- REGION



IF II I 22C FORMING n + REGION



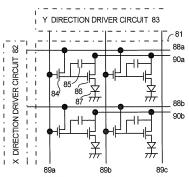
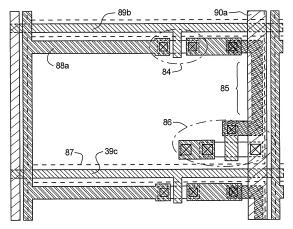
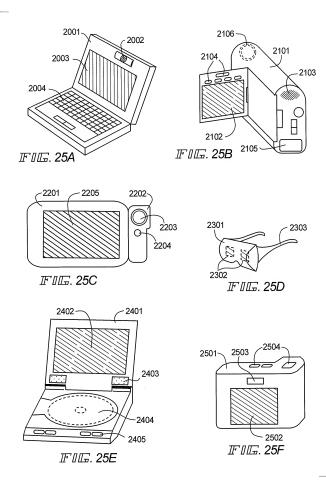


FIG. 24A EL PANEL CIRCUIT DIAGRAM



IFIII. 24B TOP VIEW OF EL PANEL PIXEL SECTION



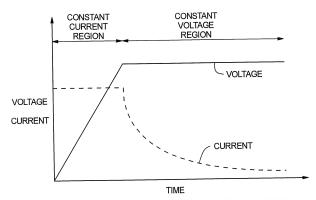
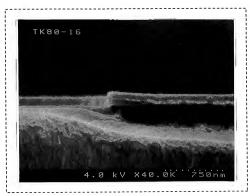
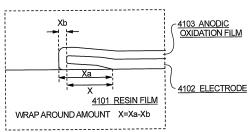


DIAGRAM SHOWING THE RELATIONSHIP BETWEEN VOLTAGE AND ELECTRIC CURRENT BETWEEN THE ELECTRODES IN A CONVENTIONAL ANODIC OXIDATION PROCESS

F115.26 PRIOR ART

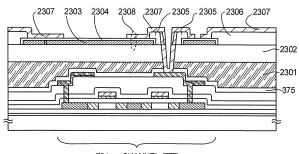




SCHEMATIC DIAGRAM OF ENLARGED ELECTRODE EDGE PORTION

IF I II. 27B

PRIOR ART



701: n-CHANNEL TFT

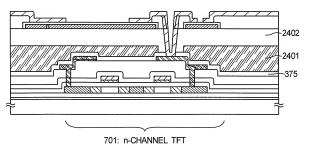
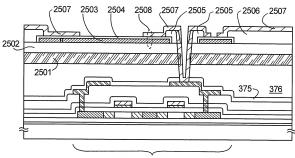
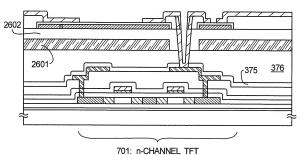


FIG. 28B



701: n-CHANNEL TFT



FIII. 29B



SEM PHOTOGRAPH (CROSS SECTION)

IF III. 30A

